

RELIABILITY REPORT





NOW PART OF



Reliability Data Report

Product Family R377

LT1394 / LT1671 / LT1711 / LT1712 /
LT1713 / LT1714 / LT1715 / LT1719 /
LT1720 / LT1721 / LT1868

Reliability Data Report

Report Number: R377

Report generated on: Mon Apr 30 10:07:24 PDT 2018

OPERATING LIFE TEST					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS (+125°C)¹	No. of FAILURES^{2,3}
SIDEBRAZE	77	9813	9813	38	0
SSOP/TSSOP	115	0014	0027	115	0
SOIC/MSOP	900	9813	0131	840	0
Totals	1,092	-	-	993	0

PRESSURE COOKER TEST AT 15 PSIG , +121 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
QFN/DFN	50	0347	0347	16	0
SSOP/TSSOP	350	9949	1419	56	0
SOT	498	0126	1246	22	0
SOIC/MSOP	2489	9810	1636	358	0
Totals	3,387	-	-	452	0

TEMP CYCLE FROM -65 TO 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
QFN/DFN	50	0347	0347	50	0
SSOP/TSSOP	340	9949	1419	177	0
SOIC/MSOP	3381	9810	1636	1094	0
SOT	550	0126	1246	55	0
Totals	4,321	-	-	1,376	0

THERMAL SHOCK FROM -65 TO 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
SSOP/TSSOP	274	9949	1419	98	0
SOT	548	0126	1246	54	0
SOIC/MSOP	1799	9810	1636	514	0
Totals	2,621	-	-	666	0

HIGH TEMPERATURE BAKE AT 175 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
SOIC/MSOP	250	0842	1448	175	0
Totals	250	-	-	175	0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55 °C, 60% Confidence Level =1.85 FITS

(3) Mean Time Between Failure in Years = 61835.2

Note: 1 FIT = 1 Failure in One Billion Hours.

Note 2: HAST, Temp Cycle & Thermal Shock are subjected to J-STD-020 MSL1 Preconditioning